EEC 116 Lecture #6: Sequential Logic

Rajeevan Amirtharajah
University of California, Davis
Jeff Parkhurst
Intel Corporation
Announcements

• Lab 3 extended, same due date as Lab 4
• HW4 issued today
Outline

• Review: Arithmetic
• Finish Transmission Gate Circuits and Multipliers
• Sequential MOS Logic Circuits: Rabaey, 7.1-7.3 (Kang & Leblebici, 8.1-8.5)
• Next Topic: Latchup and Layout Guidelines
Sequential Logic Basic Definition

• Combinational circuits’ output is a function of the circuit inputs and a delay time
  – Examples: NAND, NOR, XOR, adder, multiplier

• Sequential circuits’ output is a function of the circuit inputs, previous circuit state, and a delay time
  – Examples: Latches, flip-flops, FSMs, pipelined adders and multipliers, microprocessors
  – Sequential elements are critical to implementing techniques such as feedback or blocks such as memory
Sequential Logic Example: Mealy FSM

- Two information storage mechanisms
  - Positive feedback-based (static) circuits
  - Charge storage-based (dynamic) circuits
- Clock signal $\Phi$ controls timing of state (memory) updates
Positive Feedback: Bistability

\[ V_{i1} \quad \rightarrow \quad V_{o1} = V_{i2} \quad \rightarrow \quad V_{o2} \]

\[ V_{i1} = V_{o2} \]

\[ V_{i2} = V_{o1} \]

C (metastable)
Metastability

Gain should be larger than 1 in the transition region
Bistable Elements

- Bistable elements have two stable states or operation modes
- Cross-coupled inverters are the most basic bistable element
  - Circuit forms the basis of latches and SRAM memory
  - Stable points on the VTC are those with the lowest energy
  - Points with high energy are unstable, perturbations are amplified
Set-Reset (SR) Latch

- Change inverters to NAND or NOR gates, with second inputs = S(set) and R(reset)
- Allows control of the state of the bistable element
- One input state is not allowed
- Gating S and R with the clock prevents the latch from responding except during one phase of the clock cycle
SR Latch

• Sequential circuits: circuits which “store state”: circuits with memory elements

• Latches: store previous output value for certain input combinations

• SR latch (NAND-based):

\[
\begin{array}{ccc}
S & R & Q_{next} & \overline{Q}_{next} \\
0 & 0 & 1 & 1 \\
0 & 1 & 1 & 0 \\
1 & 0 & 0 & 1 \\
1 & 1 & Q & \overline{Q} \\
\end{array}
\]
Other Latches

• Clocked SR latch
  – Adds clock input. Latch output can only be set/reset when clk=1 (or clk=0)

• Other latch types:
  – JK latch: Removes “not allowed” state – e.g., toggles when inputs are both 1
  – T latch: Toggles when T input = 1
  – D latch: Output = D input
Latch Circuits

- Many methods for implementing latches
  - Standard CMOS gates (cross-coupled NAND, etc)
  - Transmission gates
  - Tri-state inverters

When $en=0$, $F$ is "floating", i.e. high impedance
Positive Dynamic Transmission Gate Latch

- No feedback devices
- Data stored on input capacitance of inverter I0
- Dynamic logic issues apply: leakage, capacitive coupling, charge sharing
Transmission Gate Positive Static Latch

\[ \text{Clk} \quad \overline{\text{Clk}} \]

\[ D \rightarrow \quad \text{Clk} \quad \overline{\text{Clk}} \quad \text{Clk} \quad Q \]
Positive Static Latch Timing Diagram

Clk

D

Q
NMOS Pass Gate Positive Static Latch

- Fewer devices, less area, lower clock load
- Threshold drop on internal nodes implies more static power, less noise margin
Master-Slave Flip-Flop

- By cascading two level-sensitive latches, one type of edge triggered flip-flop is created.
- JK latch can be used for first stage so that no input combinations are invalid.
- SR latch is then used for the second stage because inputs cannot be invalid.
- Rather than using logic gate-based latches, can cascade latches such as above (e.g., transmission gate dynamic or static latches).
Edge-Triggered Flip-Flops

• Types of latches/flip-flops:
  – *Level-sensitive*: output is set when clock is a certain level (0 or 1)
  – *Edge-triggered*: output can only be set on a clock edge (rising or falling)

• Advantages of edge-triggered flip-flops:
  – Data only needs to be stable at clock edge
  – Reduces *race conditions*: potential errors where an input data change travels through multiple latches during their “transparent” phase
“Safest” Edge-Triggered Flip-Flop

Master

Slave

$D$
Edge-Triggered Flip-Flop Timing Diagram

$Clk$

$D$

$Q$
Dynamic Positive Edge-Triggered FF

- No feedback devices
- Data stored on input capacitances of inverters I0 and I1
- Dynamic logic issues apply: leakage, capacitive coupling, charge sharing
Clocked Circuit Timing

• **Timing definitions:**
  
  – Clock-to-Q or Propagation Delay \( t_{\text{clkQ}} \): delay of flip-flop from clock edge to output Q
  
  – Setup Time \( t_{\text{setup}} \): amount of time *before* clock edge that data has to be stable. If data arrives after this time, it will not be latched correctly.
  
  – Hold Time \( t_{\text{hold}} \): amount of time *after* clock edge that data has to be stable.

• **It is possible to trade off setup and hold time with flip-flop circuit design**
  
  – Modify data and clock timing relationship by delaying one of the two signals
Flip-Flop: Timing Definitions

From Digital Integrated Circuits – Jan Rabaey Notes
**Maximum Clock Frequency**

- Signals must propagate out of flip-flop, through combinational logic, and be stable before next clock edge (clock period = \( T \), clock frequency = \( f \))

\[
 t_{p,FF} + t_{p,comb} + t_{\text{setup}} < T = \frac{1}{f}
\]
Staticized Dynamic Positive Edge-Triggered FF

- Use weak feedback inverters to enhance robustness
- Returns to reduced clock load static flip-flop with same sizing issues
Clock Overlap Failures

1. Both high simultaneously, race condition from \( D \) to \( Q \)
2. Node A can be driven simultaneously by \( D \) and B

Amirtharajah/Parkhurst, EEC 116 Fall 2011
Race Through and Feedback Paths

1. Both high simultaneously, race condition from \( D \) to \( Q \)
2. Node A can be driven simultaneously by \( D \) and \( B \)
Nonoverlapping Clocks Methodology

- Guarantee nonoverlap period long enough
- Note: internal nodes left high Z during nonoverlap
Tristate inverters eliminate clock overlap race condition
Zero-Zero Overlap Condition

- Both phases low simultaneously enables opposite nets
High-High Overlap Condition

- Both phases high simultaneously enables opposite nets
C²MOS Design

• Clock overlap problems eliminated as long as rise and fall times remain fast
  – Slow rise / fall times imply pullup and pulldown nets on simultaneously resulting in potential errors, static power

• Dynamic flip-flop style leaves output high Z
  – Must take care when using since output wire could be exposed to many more noise sources than internal nodes

• Mix and match styles by using C²MOS as master and other types of latch as slave

• Clock load small, but potentially larger than transmission gate dynamic latches due to PMOS sizing
Pipelining

<table>
<thead>
<tr>
<th>Clock Period</th>
<th>Adder</th>
<th>Absolute Value</th>
<th>Logarithm</th>
</tr>
</thead>
<tbody>
<tr>
<td>1</td>
<td>$a_1 + b_1$</td>
<td></td>
<td></td>
</tr>
<tr>
<td>2</td>
<td>$a_2 + b_2$</td>
<td>$</td>
<td>a_1 + b_1</td>
</tr>
<tr>
<td>3</td>
<td>$a_3 + b_3$</td>
<td>$</td>
<td>a_2 + b_2</td>
</tr>
<tr>
<td>4</td>
<td>$a_4 + b_4$</td>
<td>$</td>
<td>a_3 + b_3</td>
</tr>
<tr>
<td>5</td>
<td>$a_5 + b_5$</td>
<td>$</td>
<td>a_4 + b_4</td>
</tr>
</tbody>
</table>

From Digital Integrated Circuits – Jan Rabaey Notes
Next Topic: Latchup and Layout Guidelines

• Latchup
• Minimizing area
• Managing complexity